		pe a plus sign (+) inside the	₹ E	red to resp	Appro Patent and Trademar cond to a collection of informati	oved for use through k Office: U.S. DEPA on unless it contain	10/31/99	OF COMME	0031		
				T	Complete if Known						
Substitute for form 1449A/PTO MIL 1 9 2001 (Modified by BSTZ 6/30/99)					cation Number	09/823,085					
<u> </u>	NFC	RMATION DISCLE	KSURE ≪7/	Filing	g Dat	March 29, 2001					
		TEMENT BY APPL		First	Named Inv ntor	Jason Cong, et al.					
(us	se as	s many sheets as ne	ecessary)	Group Art Unit		Not Yet Assigned					
				Exar	miner Name	Not Yet Assigned					
Sheet	t 2 of 2				Attorney Docket Number 004120.P005						
			U.S.	PATEN	T DOCUMENTS						
Examiner Initials *		U.S.Patent Document Number	Name of Patentee or Applicant of Cited Document			Date of Publication of Cited Document MM-DD-YYYY		Filing Date if Appropria			
Kraw		5,568,395	Huang			10-22-1996		6-29-1994			
Krå		6,138,267	Murai			10-24-2000		8-18-1998			
XVdv	<u></u>	6,029,117	Devgan			2-22-2000		11-3-1997			
,									·		
				_					** - 1		
ļ	ļ										
				_							
ļ											
				GN PAT	ENT DOCUMENTS						
Examiner Initials *			nt Document		Name of Patentee or Ap			Publication of Translation			
	\vdash	Office or Country Number		Date of Cited Documer				-DD-YYYY Yes/No			
<u> </u>	\square						<u> </u>				
	H				· · · · · · · · · · · · · · · · · · ·						
			_				}				
									· · · · · · · · · · · · · · · · · · ·		
							<u></u>				
				HER DO	OCUMENTS						

OTHER DOCUMENTS								
Examiner Initials *	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published (if known).							
		<u> </u>						
		<u> </u>						

Examiner

Signature

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date

Considered

W24104

	lype a plus sign (+) erwork Reduction A		_ ` Ш	ulred to resp	Appr Patent and Tradema cond to a collection of informat	oved for use through rk Office: U.S. DEPA tion unless it contain	10/31/99	OF COMME	0031	
	for form 1449A/		6	T		nplete if Known				
(Modified by BSTZ 6/30/99) INFORMATION DISELOSURE STATEMENT BY APPLICANT					cation Number	09/823,085				
					Filing Dat March 29, 2001					
					Named Inv nt r	Jason Cong, et al.				
(use as many sheets as necessary)				Grou	p Art Unit	Not Yet Assigned				
İ					miner Name	Not Yet Assigned				
Sheet	1	of	2	Attor	ney Docket Number	004120.P005				
			U.S	. PATEN	T DOCUMENTS					
Examiner Initials *	U.S.Patent Document Number		Name of Patentee or Applicant of Cited Document		Date of Publication of Cited Document MM-DD-YYYY		Filing Date if Appropriat			
man	6,044,2	09	Alpert et al.			3-28-2000		9-15-1997		
Kran	5,859,7	76	Sato et al.			1-12-1999		8-12-1996		
WIN	5,883,8	80	Kawarabayashi			3-16-1999		1-29-1997		
Kran	5,764,5	28	Nakamura			6-9-1998		6-25-1996		
Kran	5,838,5	81	Kuroda			11-17-1998		9-30-	-1996	
MADE	5,446,674		lkeda et al.			8-29-1995		6-2-1993		
Man	5,535,133		Petschauer et al.			6-9-1996		2-9-1995		
Kran	5,555,506		Petschauer et al.			9-10-1996		2-9-	1995	
KN-W-	5,596,506		Petschauer et al.			1-21-1997		2-9-	1995	
MIN	5,825,661 Drumm					10-20-1998		5-1-1996		
			FORE	IGN PAT	ENT DOCUMENTS					
Examiner Initials *	Foreign Patent Document			Date	Name of Patentee or Applicant of Cited Document		Date of Publication o Cited Document MM-DD-YYYY		Translation? Yes/No	
	ļ									
			0	THER DO	DCUMENTS		***			
Examiner Initials •	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published (if known).								Translation? Yes/No	
										

Examiner Signature

Date Considered

424/04

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next computication to applicant.

BEST AVAILABLE COPY

Substitute f r F rm 1449A/PTO (Modified)					Complete if Known						
INFO	RMA ⁻	TION I	DISCL	.OSURE	Application Number	09	09/823,085				
					Filing Date	M	March 29, 2001				
SIAI	FIGH	IN (SE)	APP	LICANT	First Named Inventor:	Jir	Jingsheng Jason Cong				
l /		many sheet	as necess	ary)	Group Art Unit	21	2123				
(,		1 2002			Examiner Name	Uı	nknow	CEN	/ED		
Sheet \			of	1	Attorney Docket Numbe	r 00)4120.P00	AL			
OTHER ART - NO PATENT LITERATURE DOCUMENTS											
Examiner Initials*	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when a characters) item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published									
Kran	A	KAWAGUCHI, H. et al.: "Delay and Noise Formulas for Capacitively Coupled Distributed RC lines", in Proc. Asia and South Pacific Design Automation Conf., pp. 35-43, 1998.									
MAN	В	NAKAG. Intercon	NAKAGAWA, S. et al.: "On-chip Cross Talk Noise Model for Deep-Submicrometer ULSI Interconnect", Hewlett-Packard Journal, vol. 49, pp. 39-45, Aug. 1998.								
Man	С	STÖHR, T. et al.: "Analysis, Reduction and Avoidance of Crosstalk on VLSI Chips", in Proc. Int. Symp. On Physical Design, pp. 211-218, April 1998.									
MAN	D	VITTAL, A. et al.: "Crosstalk Reduction for VLSI", IEEE Trans. On Computer-aided Design of Integrated Circuits and Systems", vol. 16, pp. 290-98, 1997.									
Kran	E	DEVGAN, A.: "Efficient Coupled Noise Estimation for On-chip Interconnects", in Proc. IEEE/ACM Int. Conf. On Computer Aided Design, pp. 147-153, 1997.									
Kran	F	SEMICONDUCTOR INDUSTRY ASSOCIATION, "The National Technology Roadmap for Semiconductors", 1997 edition.									
Krzk	G	SHEPARD, K.L., et al.: "Noise in Deep Submicron Digital Design", in Proc. IEEE/ACM Int. Conf. On Computer Aided Design, pp. 524-531, 1996.									
tran	Н	SAKURAI, T.: "Closed-form Expressions for Interconnection Delay, Coupling, and Crosstalk in VLSIs", IEEE Trans. On Electron Devices, vol. 40, pp. 118-124, 1993.									
Examiner	λ	MI	9	.)		Date		17.			

Signature

Burden Hour Statement: This form is estimated to take 2.0 hours to complete. Time will vary depending upon the needs of the individual case. Any comments on the amount of time you are required to complete this form should be sent to the Chief Information Officer, Patent and Trademark Office, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Assistant Commissioner for Patents, Washington, DC 20231.

Considered

^{*}Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication.

¹Unique citation designation number. ²Applicant is to place a check mark here if English language Translation is attached.